IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

New York, New York

Yoichi MOCHIDA

Date: July 5, 2001

Serial No.: To Be Assigned

Group Art Unit: ----

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Examiner: -----

For: EXTERNAL FORCE MEASURING DEVICE

Assistant Commissioner for Patents

Washington, D.C. 20231

INFORMATION DISCLOSURE STATEMENT

Sir:

Submitted herewith is a copy of art together with a form listing the same for the convenience of the Examiner.

EXPRESS MAIL CERTIFICATE

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Respectfully submitted

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APPLICANT'S ART CITATION						N	Applicant Yoichi MOCHIDA							
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